


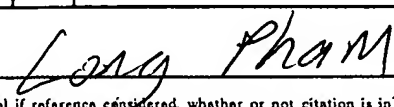
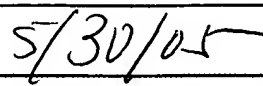


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2272	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Leonard Forbes			
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<div style="font-size: 2em; font-family: cursive;">LP</div> <div style="font-size: 3em; font-family: cursive;">↓</div>	AA	4,241,359	12/23/1980	Izumi et al			
	AB	5,441,591	08/15/1995	Forbes			
	AC	6,049,106	04/11/2000	Forbes			
	AD	5,234,535	08/10/1993	Beyer et al			
	AE	6,093,623	07/25/2000	Forbes			
	AF	6,309,950	10/30/2001	Forbes			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
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EXAMINER			DATE CONSIDERED				
<div style="font-size: 1.5em; font-family: cursive;">LON & PHAM</div>			<div style="font-size: 1.5em; font-family: cursive;">5/30/05</div>				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M121-3372		SERIAL NO. 10871,229	
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
LP	AA	10/46,315	Forbes (as amended 11/1/2004)			05/21/2003	
	AB						
	AC						
	AD						
	AE						
	AF						
	AO						
FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AH							
AI							
AJ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AK							
EXAMINER		Long Pham		DATE CONSIDERED		5/30/05	
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AH						
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK		C. Harendt et al. "Silicon on Insulator Material by Wafer Bonding," J. Electronic Materials, vol. 20, no. 3, pp. 267-277, March 1991				
	AL		S.M. Sze, "Physics of Semiconductor Devices, John Wiley & Sons, New York (1981), pgs. 850-851.				
	AM		J.B. Laksy, "Wafer Bonding for Silicon on Insulator Technologies," Appl. Phys. Letters, Vol. 48, No. 1, pp. 78-80, Jan. 1986.				
	AN		M. Breul et al., "Smart-Cut: a New Silicon on Insulator Material Technology Based on Hydrogen Implantation and Wafer Bonding," Proc. 1996 Int. Conf. On Solid State Devices and Materials, Japan. J. Appl. Phys., Part 1, Vol. 36, No. 3B, pp. 1636-41, 1996				
	AO		T. Suni et al, "Effects of Plasma Activation on Hydrophilic Bonding of Si and SiO ₂ ," J. Electrochem. Soc., Vol. 149, No. 6, pp. G348-51, June 2002.				
EXAMINER				DATE CONSIDERED			
							
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